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Notice of References Cited					Examiner		Art Unit	Dag		
					Donghai D. Nguyen 3729					
U.S. PATENT DOCUMENTS										
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY		Name				Classification	
X	Α	US-4,573,265	03-1986	Conaw	ay et al.			29/879		
Χ	В	US-5,429,656	07-1995	Hauner et al.				75/232		
	С	US-								
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	G	US-								
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FOREIGN PATENT DOCUMENTS										
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NON-PATENT DOCUMENTS										
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYYY format are publication dates. Classifications may be US or foreign.

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